

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/813,025	YUAN, TI-WEN
<b>Examiner</b>	<b>Art Unit</b>	
Nhan T. Le	2618	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner